

# NGTB20N120IHSWG

## IGBT

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop (FS) Trench construction, and provides superior performance in demanding switching applications, offering both low on-state voltage and minimal switching loss. The IGBT is well suited for resonant or soft switching applications. Incorporated into the device is a rugged co-packaged free wheeling diode with a low forward voltage.

### Features

- Low Saturation Voltage using Trench with Field Stop Technology
- Low Switching Loss Reduces System Power Dissipation
- Optimized for Low Case Temperature in IH Cooker Application
- Low Gate Charge
- These are Pb-Free Devices

### Typical Applications

- Inductive Heating
- Consumer Appliances
- Soft Switching

### ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-emitter voltage	$V_{CES}$	1200	V
Collector current @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	$I_C$	40 20	A
Pulsed collector current, $T_{pulse}$ limited by $T_{Jmax}$	$I_{CM}$	120	A
Diode forward current @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	$I_F$	40 20	A
Diode pulsed current, $T_{pulse}$ limited by $T_{Jmax}$	$I_{FM}$	120	A
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Power Dissipation @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	$P_D$	156 62.5	W
Operating junction temperature range	$T_J$	-55 to +150	$^\circ\text{C}$
Storage temperature range	$T_{stg}$	-55 to +150	$^\circ\text{C}$
Lead temperature for soldering, 1/8" from case for 5 seconds	$T_{SLD}$	260	$^\circ\text{C}$

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



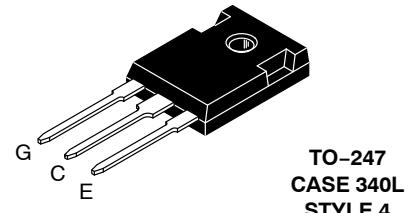
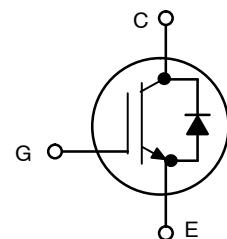
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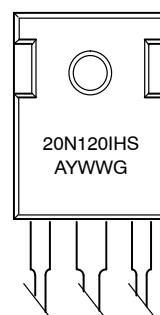
**20 A, 1200 V**

**$V_{CEsat} = 2.10 \text{ V}$**

**$E_{off} = 0.65 \text{ mJ}$**



### MARKING DIAGRAM



A = Assembly Location  
Y = Year  
WW = Work Week  
G = Pb-Free Package

### ORDERING INFORMATION

Device	Package	Shipping
NGTB20N120IHSWG	TO-247 (Pb-Free)	30 Units / Rail

# NGTB20N120IHSWG

## THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{\theta JC}$	0.80	°C/W
Thermal resistance junction-to-case, for Diode	$R_{\theta JC}$	2.0	°C/W
Thermal resistance junction-to-ambient	$R_{\theta JA}$	40	°C/W

## ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
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### STATIC CHARACTERISTIC

Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V}, I_C = 500 \mu\text{A}$	$V_{(BR)CES}$	1200	–	–	V
Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}, I_C = 20 \text{ A}$ $V_{GE} = 15 \text{ V}, I_C = 20 \text{ A}, T_J = 150^\circ\text{C}$	$V_{CEsat}$	– –	2.10 2.5	2.4 –	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_C = 50 \mu\text{A}$	$V_{GE(th)}$	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate-emitter short-circuited	$V_{GE} = 0 \text{ V}, V_{CE} = 1200 \text{ V}$ $V_{GE} = 0 \text{ V}, V_{CE} = 1200 \text{ V}, T_J = 150^\circ\text{C}$	$I_{CES}$	– –	– –	0.5 2.0	mA
Gate leakage current, collector-emitter short-circuited	$V_{GE} = 20 \text{ V}, V_{CE} = 0 \text{ V}$	$I_{GES}$	–	–	100	nA

### DYNAMIC CHARACTERISTIC

Input capacitance	$V_{CE} = 20 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$	$C_{ies}$	–	3600	–	pF
Output capacitance		$C_{oes}$	–	90	–	
Reverse transfer capacitance		$C_{res}$	–	65	–	
Gate charge total	$V_{CE} = 600 \text{ V}, I_C = 20 \text{ A}, V_{GE} = 15 \text{ V}$	$Q_g$	–	155	–	nC
Gate to emitter charge		$Q_{ge}$	–	30	–	
Gate to collector charge		$Q_{gc}$	–	70	–	

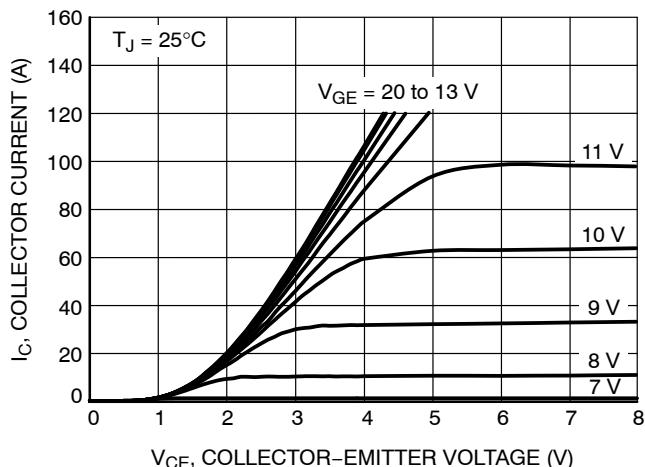
### SWITCHING CHARACTERISTIC, INDUCTIVE LOAD

Turn-off delay time	$T_J = 25^\circ\text{C}$ $V_{CC} = 600 \text{ V}, I_C = 20 \text{ A}$ $R_g = 10 \Omega$ $V_{GE} = 0 \text{ V}/15\text{V}$	$t_{d(off)}$	–	160	–	ns
Fall time		$t_f$	–	160	–	
Turn-off switching loss		$E_{off}$	–	0.65	–	
Turn-off delay time	$T_J = 125^\circ\text{C}$ $V_{CC} = 600 \text{ V}, I_C = 20 \text{ A}$ $R_g = 10 \Omega$ $V_{GE} = 0 \text{ V}/15\text{V}$	$t_{d(off)}$	–	167	–	ns
Fall time		$t_f$	–	205	–	
Turn-off switching loss		$E_{off}$	–	1.20	–	

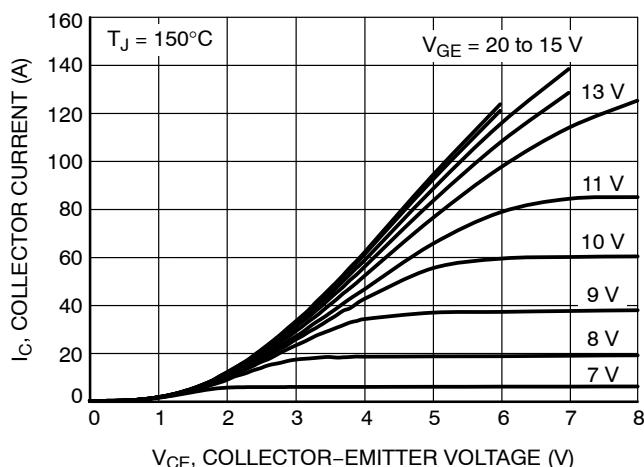
### DIODE CHARACTERISTIC

Forward voltage	$V_{GE} = 0 \text{ V}, I_F = 20 \text{ A}$ $V_{GE} = 0 \text{ V}, I_F = 20 \text{ A}, T_J = 150^\circ\text{C}$	$V_F$	– –	1.55 1.65	1.75 –	V
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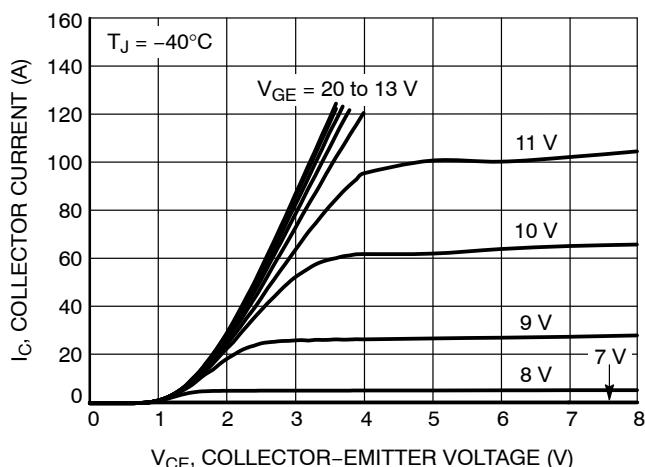
**TYPICAL CHARACTERISTICS**



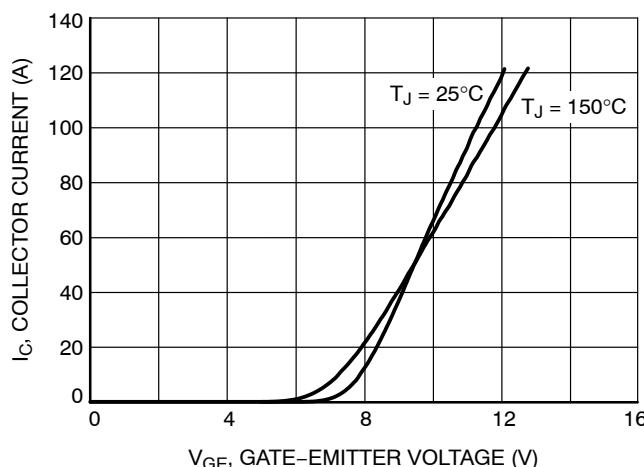
**Figure 1. Output Characteristics**



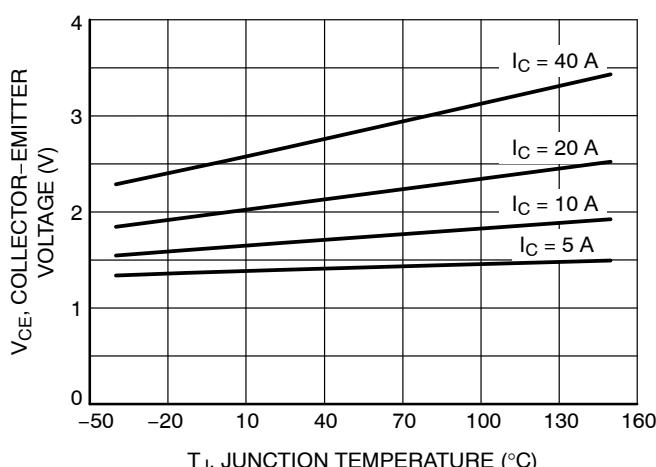
**Figure 2. Output Characteristics**



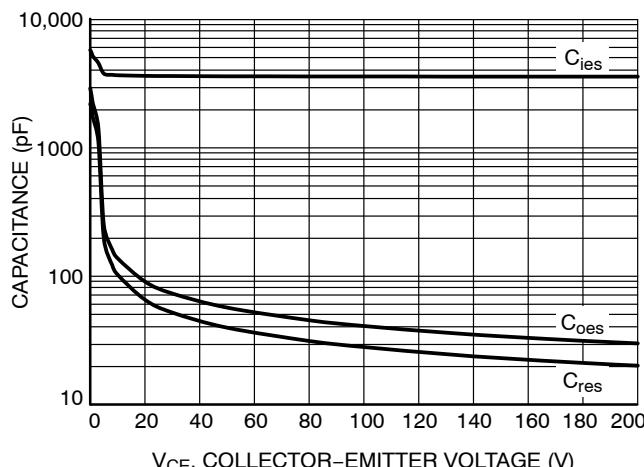
**Figure 3. Output Characteristics**



**Figure 4. Typical Transfer Characteristics**

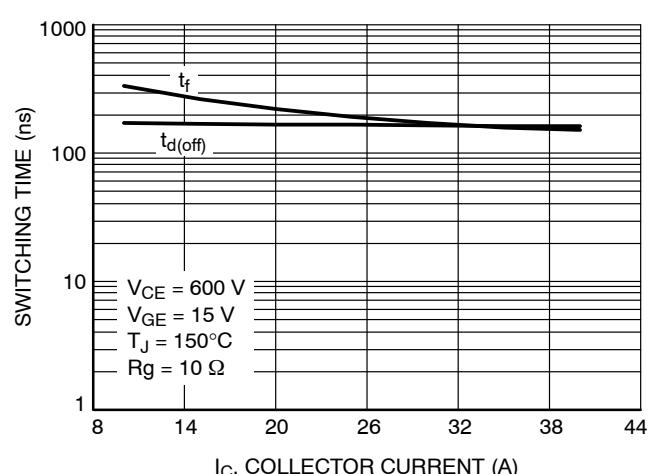
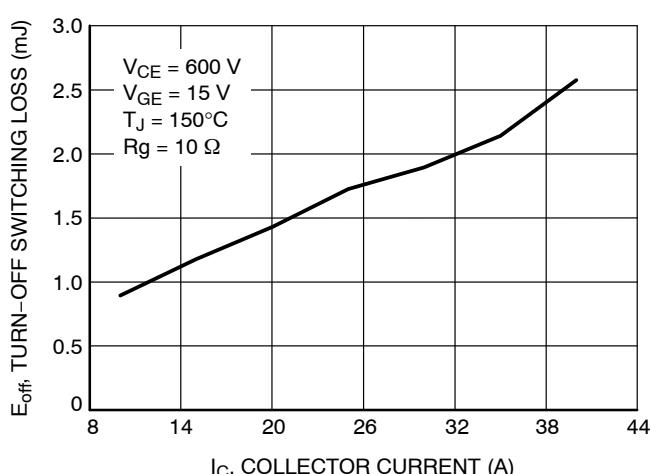
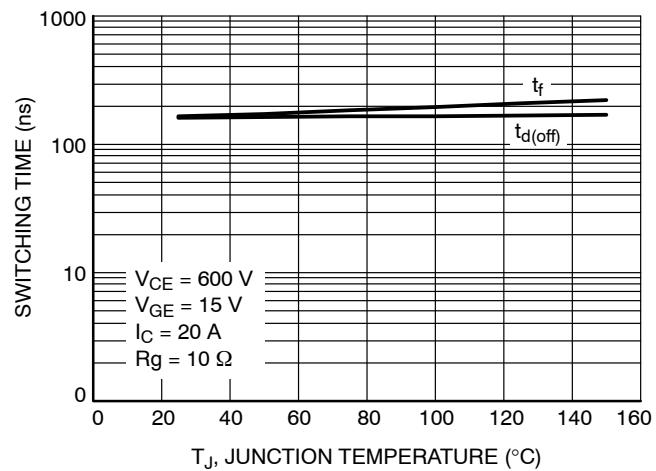
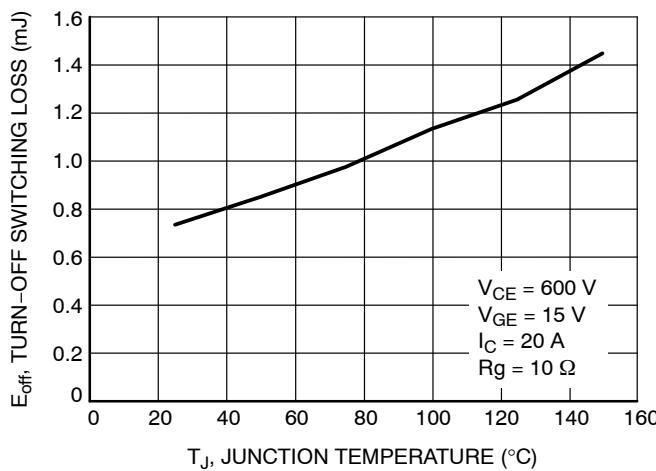
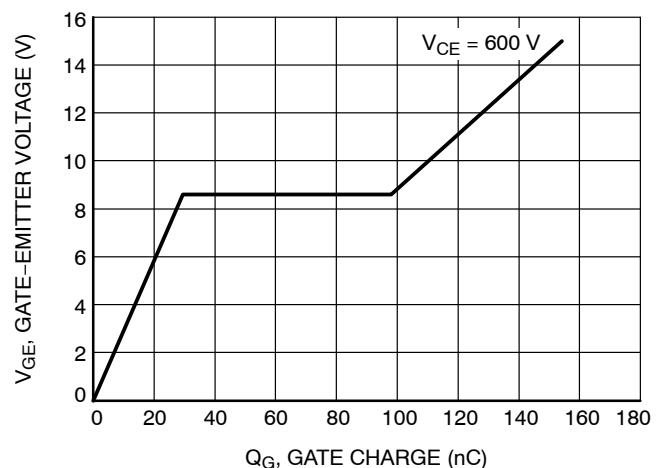
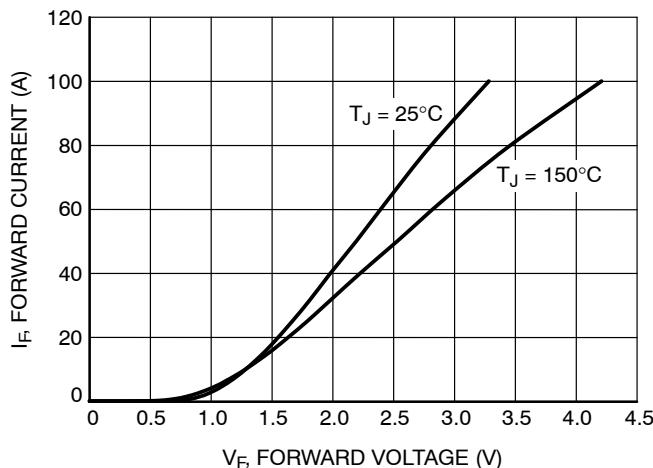


**Figure 5.  $V_{CE(\text{sat})}$  vs.  $T_J$**



**Figure 6. Typical Capacitance**

## TYPICAL CHARACTERISTICS



## TYPICAL CHARACTERISTICS

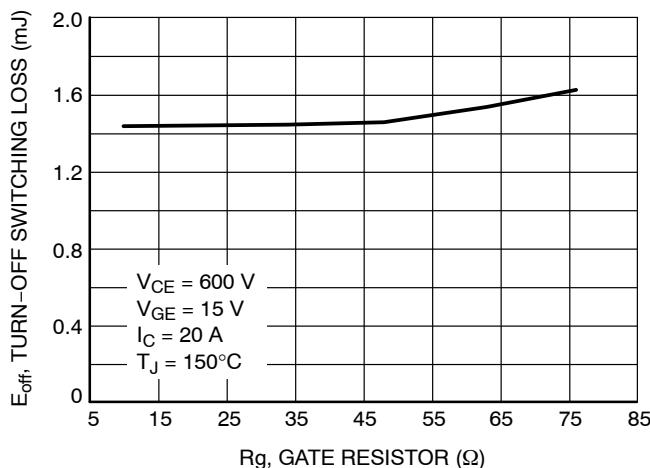


Figure 13. Switching Loss vs.  $R_g$

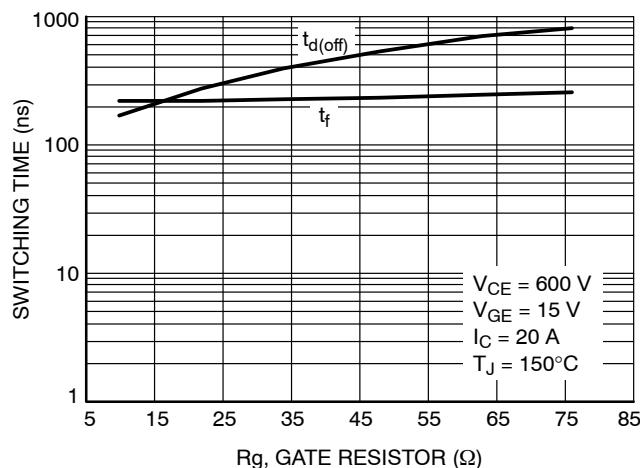


Figure 14. Switching Time vs.  $R_g$

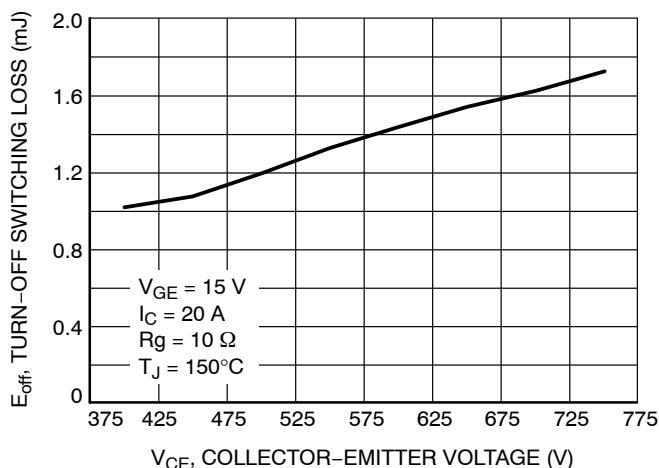


Figure 15. Switching Loss vs.  $V_{CE}$

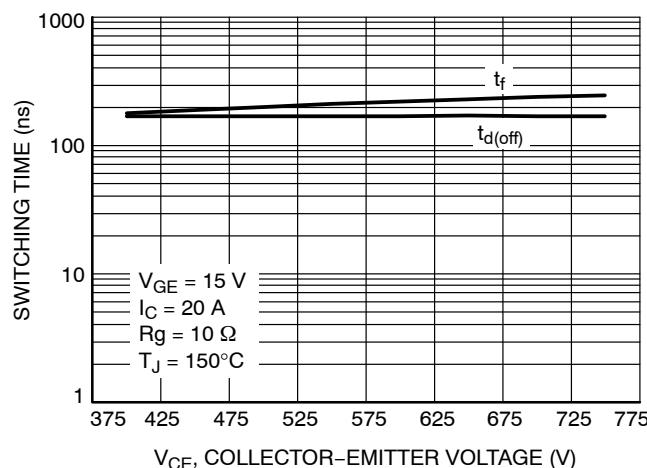


Figure 16. Switching Time vs.  $V_{CE}$

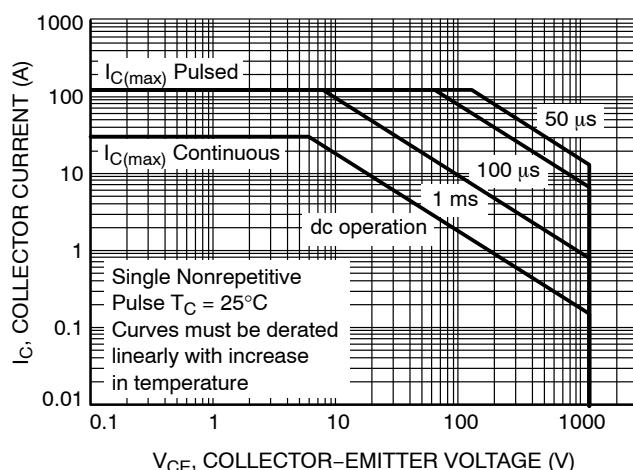


Figure 17. Safe Operating Area

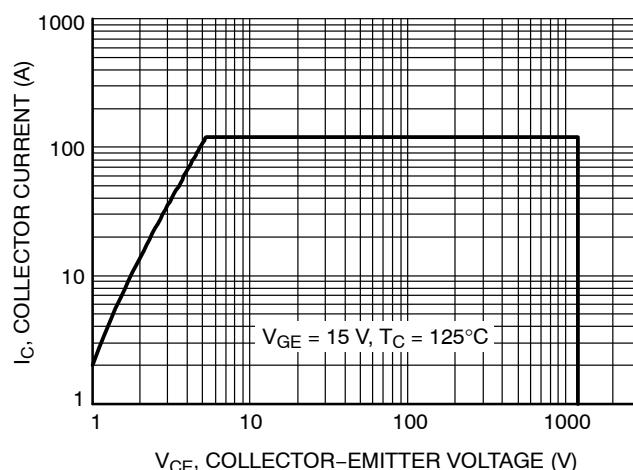


Figure 18. Reverse Bias Safe Operating Area

## TYPICAL CHARACTERISTICS

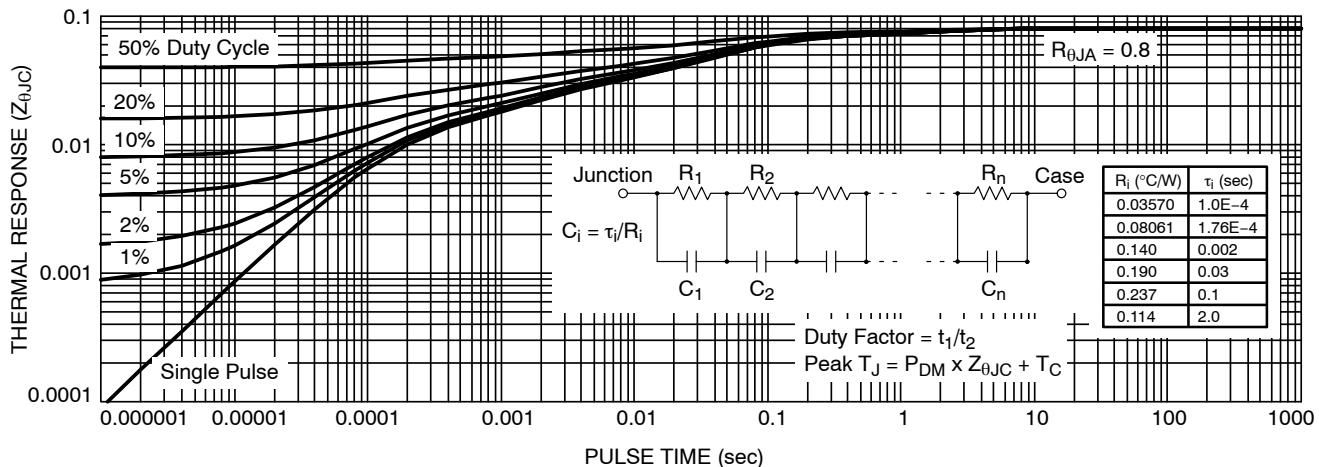


Figure 19. IGBT Transient Thermal Impedance

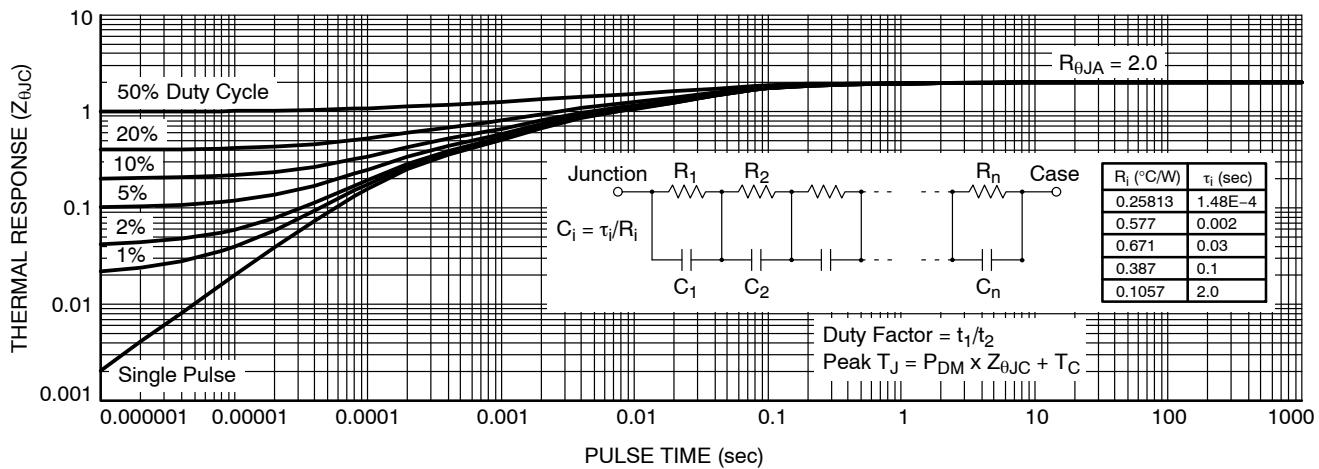


Figure 20. Diode Transient Thermal Impedance

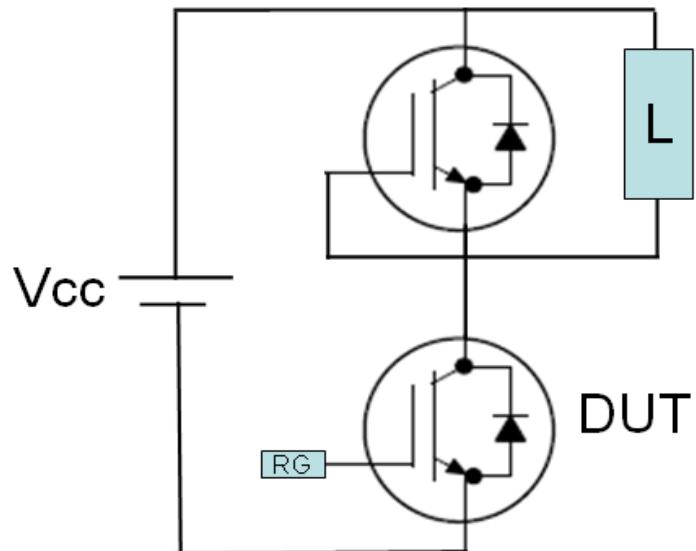
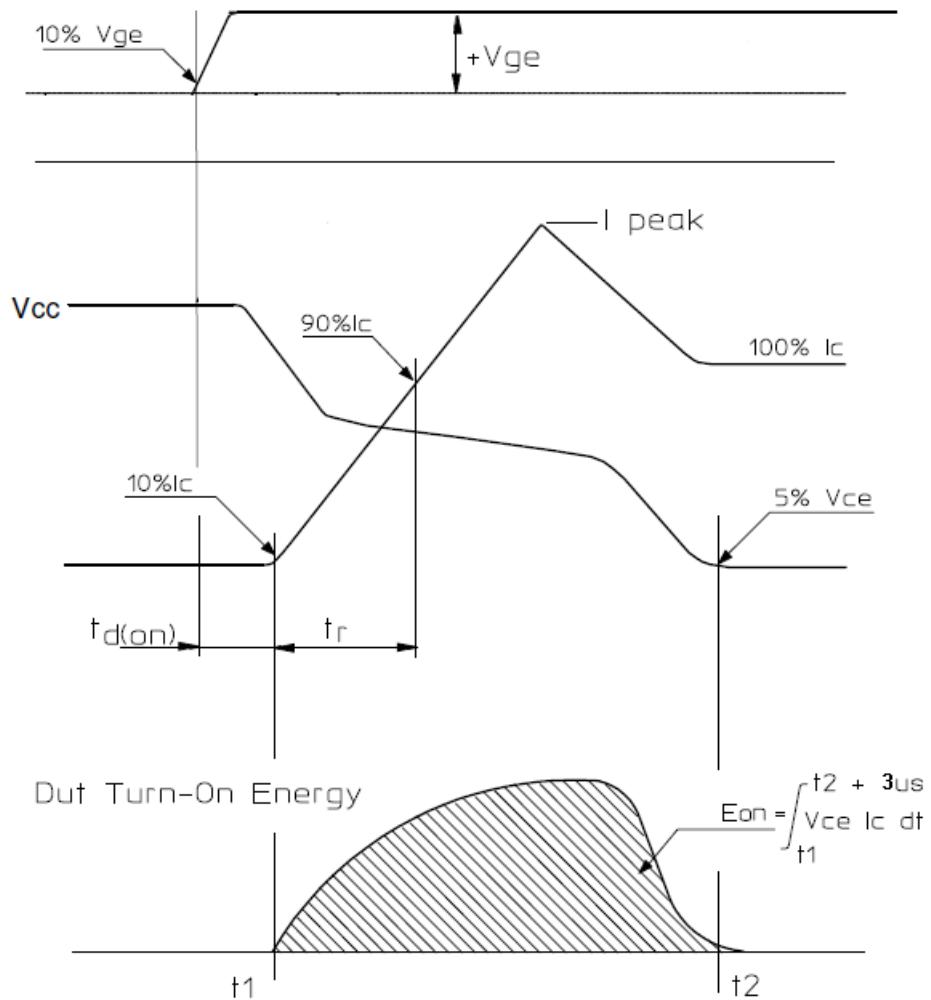


Figure 21. Test Circuit for Switching Characteristics



**Figure 22. Definition of Turn On Waveform**

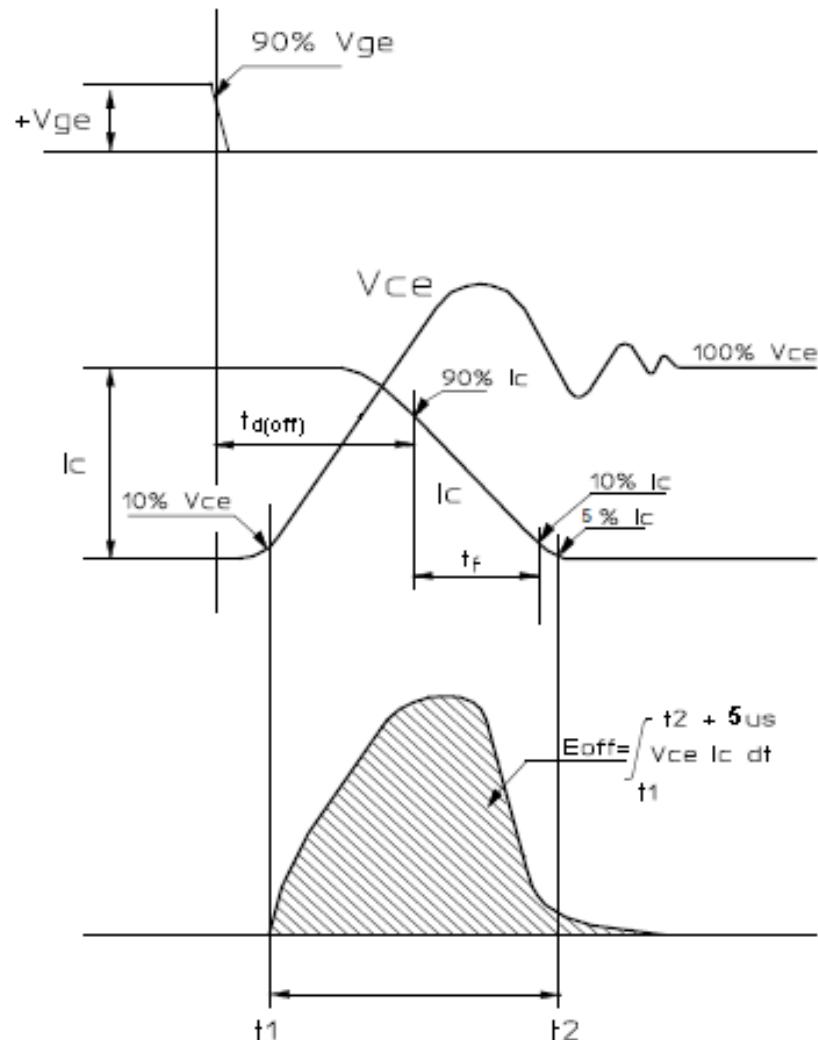
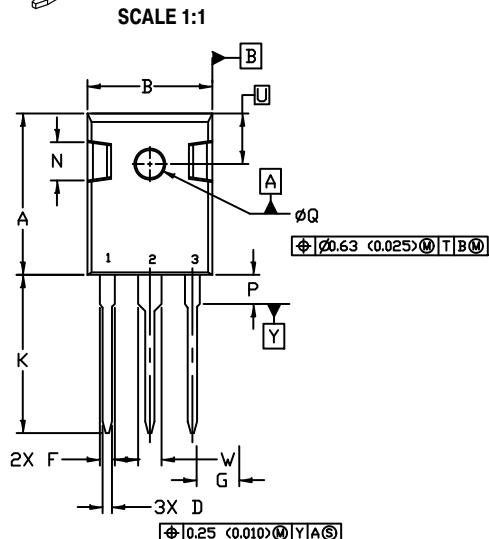
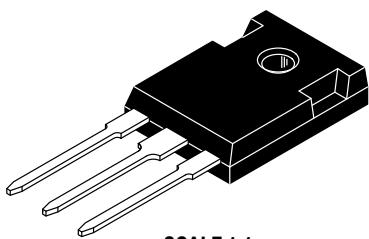


Figure 23. Definition of Turn Off Waveform

**MECHANICAL CASE OUTLINE  
PACKAGE DIMENSIONS**

**onsemi**<sup>TM</sup>

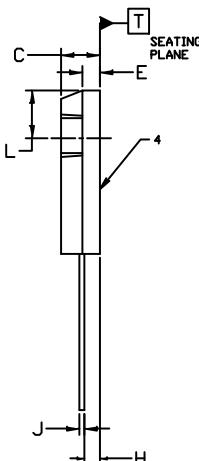


**TO-247  
CASE 340L  
ISSUE G**

DATE 06 OCT 2021

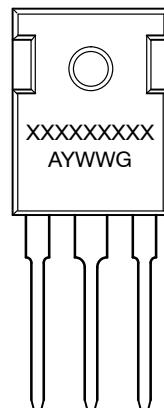
NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER



DIM	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	20.32	21.08	0.800	0.830
B	15.75	16.26	0.620	0.640
C	4.70	5.30	0.185	0.209
D	1.00	1.40	0.040	0.055
E	1.90	2.60	0.075	0.102
F	1.65	2.13	0.065	0.084
G	5.45	BSC	0.215	BSC
H	1.50	2.49	0.059	0.098
J	0.40	0.80	0.016	0.031
K	19.81	20.83	0.780	0.820
L	5.40	6.20	0.212	0.244
N	4.32	5.49	0.170	0.216
P	-----	4.50	-----	0.177
Q	3.55	3.65	0.140	0.144
U	6.15	BSC	0.242	BSC
W	2.87	3.12	0.113	0.123

**GENERIC  
MARKING DIAGRAM\***



STYLE 1:  
PIN 1. GATE  
2. DRAIN  
3. SOURCE  
4. DRAIN

STYLE 2:  
PIN 1. ANODE  
2. CATHODE (S)  
3. ANODE 2  
4. CATHODES (S)

STYLE 3:  
PIN 1. BASE  
2. COLLECTOR  
3. Emitter  
4. COLLECTOR

STYLE 4:  
PIN 1. GATE  
2. COLLECTOR  
3. Emitter  
4. COLLECTOR

XXXXXX = Specific Device Code  
A = Assembly Location  
Y = Year  
WW = Work Week  
G = Pb-Free Package

STYLE 5:  
PIN 1. CATHODE  
2. ANODE  
3. GATE  
4. ANODE

STYLE 6:  
PIN 1. MAIN TERMINAL 1  
2. MAIN TERMINAL 2  
3. GATE  
4. MAIN TERMINAL 2

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

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